PHKD3NQ10T

Dual N-channel TrenchMOS standard level FET

Rev. 02 — 16 December 2010　　　　　　　**Product data sheet**

1. Product profile

1.1 General description

Dual standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Suitable for high frequency applications due to fast switching characteristics
- Suitable for use in compact designs due to low profile

1.3 Applications

- DC-to-DC converters
- Motor and relay drivers

1.4 Quick reference data
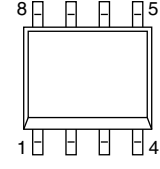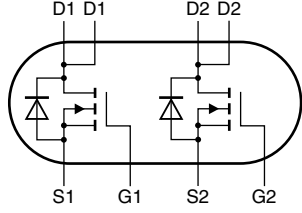
Table 1.　Quick reference data

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{DS}	drain-source voltage	$T_j \geq 25\ °C$; $T_j \leq 150\ °C$	-	-	100	V
I_D	drain current	$T_{sp} = 25\ °C$; One MOSFET conducting	-	-	3	A
P_{tot}	total power dissipation	$T_{sp} = 25\ °C$	-	-	2	W
Static characteristics						
R_{DSon}	drain-source on-state resistance	$V_{GS} = 10\ V$; $I_D = 1.5\ A$; $T_j = 25\ °C$	-	70	90	mΩ
Dynamic characteristics						
Q_{GD}	gate-drain charge	$V_{GS} = 10\ V$; $I_D = 3\ A$; $V_{DS} = 80\ V$; $T_j = 25\ °C$	-	8	-	nC

2. Pinning information

Table 2.   **Pinning information**

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S1	source1		
2	G1	gate1		
3	S2	source2		
4	G2	gate2		
5	D	drain2	**SOT96-1 (SO8)**	
6	D	drain2		
7	D	drain1		
8	D	drain1		*mbk725*

3. Ordering information

Table 3.   **Ordering information**

| Type number	Package		Version
	Name	**Description**	
PHKD3NQ10T	SO8	plastic small outline package; 8 leads; body width 3.9 mm	SOT96-1

4. Limiting values

Table 4.   **Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

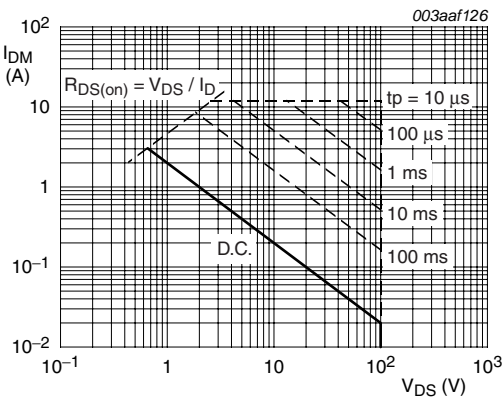| Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \geq 25\ °C$; $T_j \leq 150\ °C$	-	100	V
V_{DGR}	drain-gate voltage	$T_j \leq 150\ °C$; $T_j \geq 25\ °C$; $R_{GS} = 20\ k\Omega$	-	100	V
V_{GS}	gate-source voltage		-20	20	V
I_D	drain current	$T_{sp} = 25\ °C$; both MOSFETs conducting	-	2.2	A
		$T_{sp} = 70\ °C$; one MOSFET conducting	-	2.4	A
		$T_{sp} = 70\ °C$; both MOSFETs conducting	-	1.7	A
		$T_{sp} = 25\ °C$; One MOSFET conducting	-	3	A
I_{DM}	peak drain current	$T_{sp} = 25\ °C$; pulsed; One MOSFET conducting	-	12	A
P_{tot}	total power dissipation	$T_{sp} = 70\ °C$	-	1.3	W
		$T_{sp} = 25\ °C$	-	2	W
T_{stg}	storage temperature		-65	150	°C
T_j	junction temperature		-65	150	°C
Source-drain diode					
I_S	source current	$T_{sp} = 25\ °C$	-	2	A
I_{SM}	peak source current	$T_{sp} = 25\ °C$; pulsed; $t_p \leq 10\ s$	-	12	A
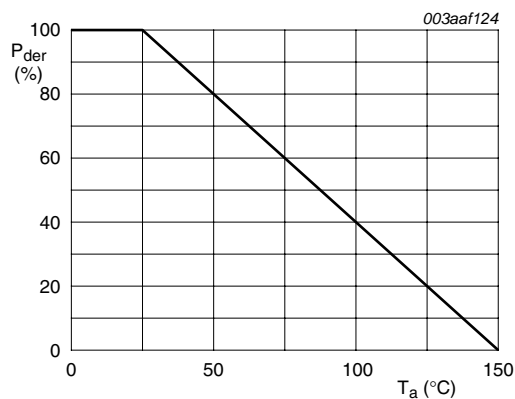
$$P_{der} = \frac{P_{tot}}{P_{tot(25°C)}} \times 100\%$$

Fig 1. Normalized total power dissipation as a function of mounting base temperature
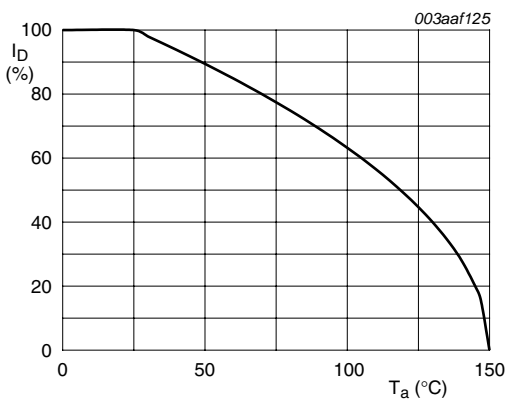
$$I_{der} = \frac{I_D}{I_{D(25°C)}} \times 100\%$$

Fig 2. Normalized continuous drain current as a function of mounting base temperature

$T_{mb} = 25$ °C; I_{DM} is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 5. **Thermal characteristics**

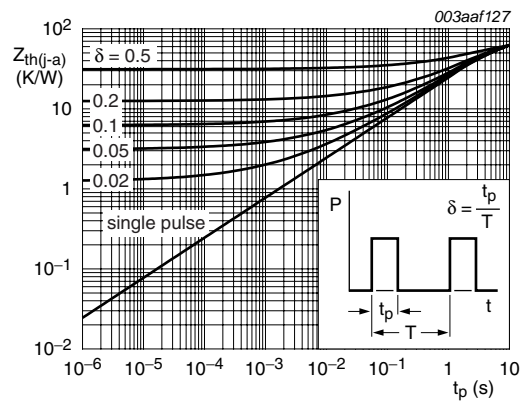| Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	Surface mounted on FR4 board ; either or both MOSFETs conducting ; t ≤ 10 sec	-	-	62.5	K/W
		Surface mounted on FR4 board ; either or both MOSFETs conducting	-	150	-	K/W

Fig 4. **Transient thermal impedance from junction to mounting base as a function of pulse duration**

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6. Characteristics

Table 6. **Characteristics**

| Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Static characteristics						
$V_{(BR)DSS}$	drain-source breakdown voltage	I_D = 250 µA; V_{GS} = 0 V; T_j = -55 °C	89	-	-	V
		I_D = 250 µA; V_{GS} = 0 V; T_j = 25 °C	100	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	I_D = 1 mA; V_{DS} = V_{GS}; T_j = -55 °C	-	-	6	V
		I_D = 1 mA; V_{DS} = V_{GS}; T_j = 150 °C	1.1	-	-	V
		I_D = 1 mA; V_{DS} = V_{GS}; T_j = 25 °C	2	3	4	V
I_{DSS}	drain leakage current	V_{DS} = 100 V; V_{GS} = 0 V; T_j = 25 °C	-	0.05	10	µA
		V_{DS} = 100 V; V_{GS} = 0 V; T_j = 150 °C	-	-	100	µA
I_{GSS}	gate leakage current	V_{GS} = 20 V; V_{DS} = 0 V; T_j = 25 °C	-	10	100	nA
		V_{GS} = -20 V; V_{DS} = 0 V; T_j = 25 °C	-	10	100	nA
R_{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I_D = 1.5 A; T_j = 150 °C	-	-	216	mΩ
		V_{GS} = 10 V; I_D = 1.5 A; T_j = 25 °C	-	70	90	mΩ
Dynamic characteristics						
$Q_{G(tot)}$	total gate charge	I_D = 3 A; V_{DS} = 80 V; V_{GS} = 10 V; T_j = 25 °C	-	21	-	nC
Q_{GS}	gate-source charge		-	2.5	-	nC
Q_{GD}	gate-drain charge		-	8	-	nC
C_{iss}	input capacitance	V_{DS} = 20 V; V_{GS} = 0 V; f = 1 MHz; T_j = 25 °C	-	633	-	pF
C_{oss}	output capacitance		-	103	-	pF
C_{rss}	reverse transfer capacitance		-	61	-	pF
$t_{d(on)}$	turn-on delay time	V_{DS} = 50 V; R_L = 15 Ω; V_{GS} = 10 V; $R_{G(ext)}$ = 5.6 Ω; T_j = 25 °C	-	6	-	ns
t_r	rise time		-	12	-	ns
$t_{d(off)}$	turn-off delay time		-	20	-	ns
t_f	fall time		-	10	-	ns
L_D	internal drain inductance	measured from drain lead to centre of die ; T_j = 25 °C	-	2.5	-	nH
L_S	internal source inductance	measured from source lead to source bond pad ; T_j = 25 °C	-	5	-	nH
Source-drain diode						
V_{SD}	source-drain voltage	I_S = 2 A; V_{GS} = 0 V; T_j = 25 °C	-	0.8	1.2	V
t_{rr}	reverse recovery time	I_S = 2 A; dI_S/dt = -100 A/µs; V_{GS} = 0 V; V_{DS} = 25 V; T_j = 25 °C	-	55	-	ns
Q_r	recovered charge		-	135	-	nC
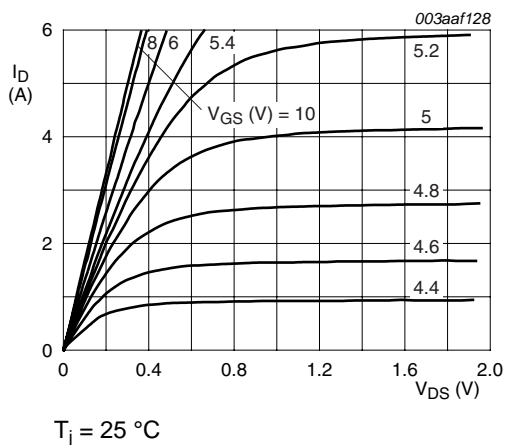
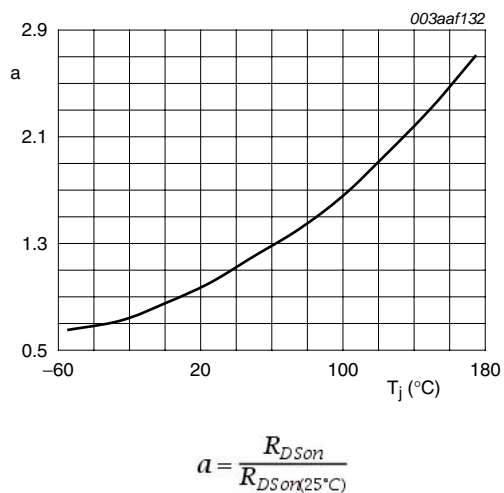**Fig 5.** **Output characteristics: drain current as a function of drain-source voltage; typical values**

$T_j = 25 °C$
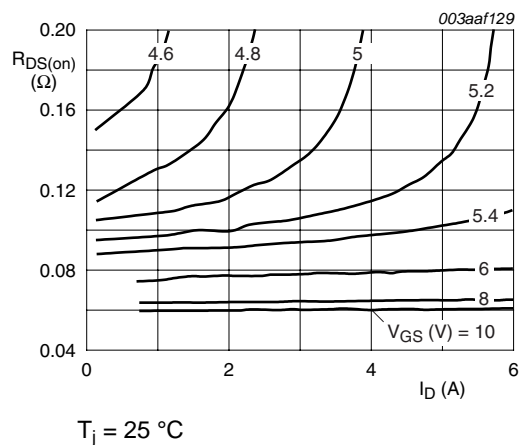
Fig 6. **Drain-source on-state resistance as a function of drain current; typical values**

$T_j = 25 °C$

$V_{DS} > I_D$ x R_{DSon}
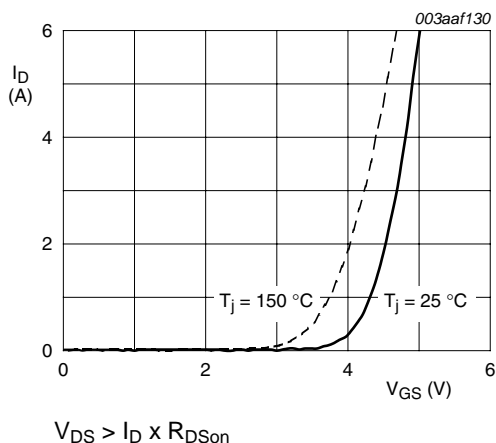
Fig 7. **Transfer characteristics: drain current as a function of gate-source voltage; typical values**

$V_{DS} > I_D$ x R_{DSon}
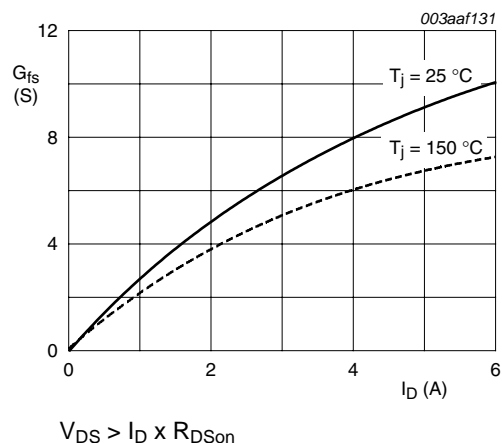
Fig 8. **Forward transconductance as a function of drain current; typical values**

$$a = \frac{R_{DSon}}{R_{DSon(25°C)}}$$

Fig 9. **Normalized drain-source on-state resistance factor as a function of junction temperature**

$I_D = 1$ mA; $V_{DS} = V_{GS}$
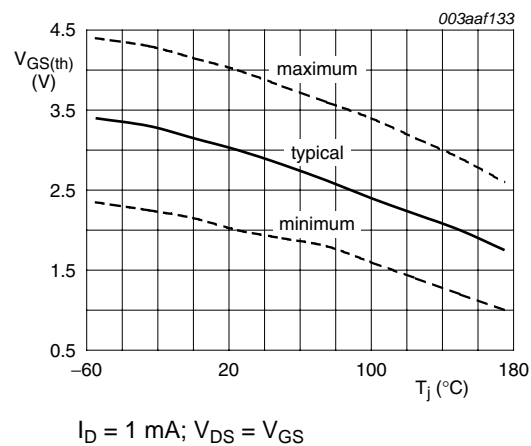
Fig 10. **Gate-source threshold voltage as a function of junction temperature**

$T_j = 25\ °C; V_{DS} = V_{GS}$
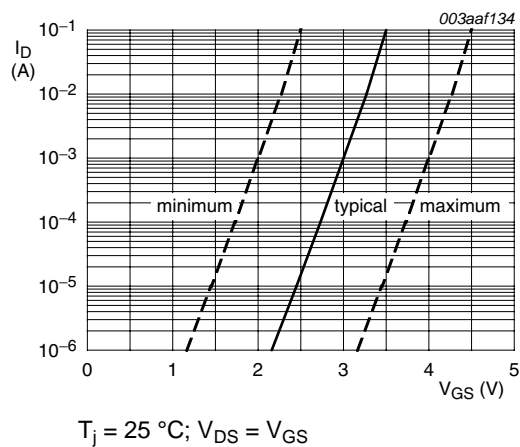
Fig 11. Sub-threshold drain current as a function of gate-source voltage

$V_{GS} = 0\ V; f = 1\ MHz$
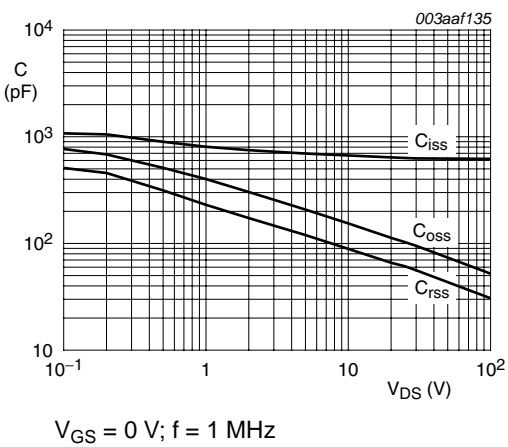
Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

$T_j = 25\ °C; I_D = 3\ A$

Fig 13. Gate-source voltage as a function of gate charge; typical values

$V_{GS} = 0\ V$
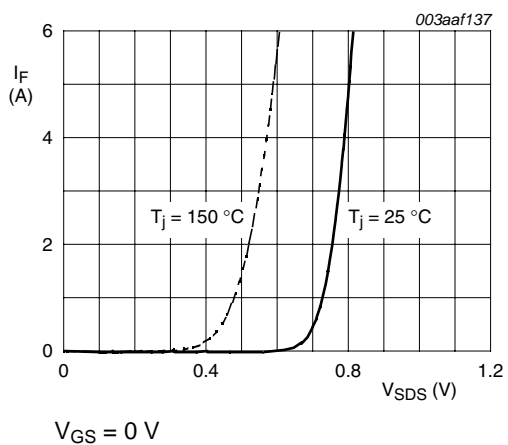
Fig 14. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

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7. Package outline

SO8: plastic small outline package; 8 leads; body width 3.9 mm

SOT96-1
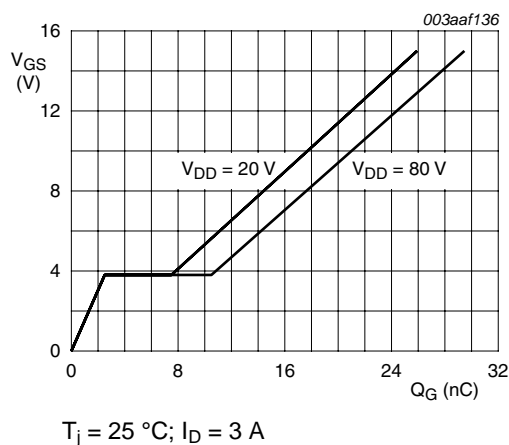

DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A₁	A₂	A₃	bp	c	D(1)	E(2)	e	HE	L	Lp	Q	v	w	y	Z(1)	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	5.0 4.8	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8° 0°
inches	0.069	0.010 0.004	0.057 0.049	0.01	0.019 0.014	0.0100 0.0075	0.20 0.19	0.16 0.15	0.05	0.244 0.228	0.041	0.039 0.016	0.028 0.024	0.01	0.01	0.004	0.028 0.012	

Notes

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

2. Plastic or metal protrusions of 0.25 mm (0.01 inch) maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT96-1	076E03	MS-012				99-12-27 03-02-18

Fig 15. Package outline SOT96-1 (SO8)

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8. Revision history

Table 7.   Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PHKD3NQ10T v.2	20101216	Product data sheet	-	PHKD3NQ10T v.1
Modifications:	• The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. • Legal texts have been adapted to the new company name where appropriate.			
PHKD3NQ10T v.1	19990801	Product specification	-	-

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9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1]   Please consult the most recently issued document before initiating or completing a design.

[2]   The term 'short data sheet' is explained in section "Definitions".

[3]   The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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